

Declaration of Compliance

Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 (RoHS II) and Delegated Directive (EU) 2015/863 of the European Parliament and Council of March 31, 2015 (RoHS III) on the restriction of the use of certain hazardous substances in electrical and electronic equipment)

Regulatory Model	Product Name
NXS1U1NS10G610*	Converged Server/Storage System

^{*} NXS1U1NS10G610 Series will cover NX-3170-G7 models and its options, upgrades and spares.

The above listed product or product family has been verified to be in compliance with the European Union Restriction of Hazardous Substances, Directive 2011/65/EU and Delegated Directive (EU) 2015/863.

This declaration is based in part on information provided to Nutanix by its suppliers. To the best of our knowledge, the above listed product does not contain Lead (0.1 % w/w), Mercury (0.1 % w/w), Cadmium (0.01 % w/w), Hexavalent chromium (0.1 % w/w), Polybrominated biphenyls (PBB) (0.1 % w/w), Polybrominated diphenyl ethers (PBDE) (0.1 % w/w), Bis(2-Ethylhexyl) phthalate (DEHP) (0.1 % w/w), Benzyl butyl phthalate (BBP) (0.1 % w/w), Dibutyl phthalate (DBP) (0.1 % w/w), or Diisobutyl phthalate (DIBP) (0.1 % w/w) except where valid exemptions have been granted by the European Union.

The following exemptions were used to achieve compliance:

- 6a(i). Lead as an alloying element in steel for machining purposes containing up to 0.35% lead by weight and in batch hot dip galvanised steel components containing up to 0.2% lead by weight (Expires July 21, 2021)
- 6c. Copper alloy containing up to 4 % lead by weight. (Expires July 21, 2021)
- 7a. Lead in high melting temperature type solders (i.e. lead-based alloys containing 85% by weight or more lead). (Expires July 21, 2021)
- 7c(i). Electrical and electronic components containing lead in a glass or ceramic other than dielectric
 ceramic in capacitors, e.g. piezoelectronic devices, or in a glass or ceramic matrix compound. (Expires
 July 21, 2021)
- 13(a). Lead in white glasses used for optical applications. (Expires July 21, 2021)
- 15(a). Lead in solders to samplete a viable electrical connection between the semiconductor die and
 carrier within integrated circuit flip chip packages where at least one of the following criteria applies:

A semiconductor technology node of 90 nm or larger.

A single die of 300 mm2 or larger in any semiconductor technology node.

Stacked die packages with die of 300 mm2 or larger, or silicon interposers of 300 mm2 or larger.

Scott Llovd

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